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- Semiconductor memory device with a test mode.
- (57) A semiconductor memory device characterized by the fact that the dynamic test time of the semiconductor memory device can be shortened, and the power consumption can be cut.

In the dynamic test for the semiconductor memory device in this invention, multiple word lines are selected at the same time with a prescribed interval corresponding to the element isolation layout. As the word lines are selected corresponding to the element isolating layout, the interference caused by the element isolation state can be excluded. Since multiple word lines are selected at the same time, the time of operation can be shortened. Since the word lines are maintained in the selected state while the sense amplifiers are not reset, there is no increase in the power consumption although multiple word lines are selected at the same time.

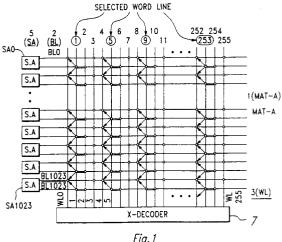


Fig. 1



EUROPEAN SEARCH REPORT

Application Number EP 93 11 2936

DOCUMENTS CONSIDERED TO BE RELEVANT Citation of document with indication, where appropriate,			Relevant	CLASSIFICATION OF THE
Acceptory	of relevant p	assages	to claim	APPLICATION (Int.CL.5) G11C29/00
	* abstract; figure: * page 3, line 1 - * page 8, line 29 - * claims 1-10 *	s 3-5 *		
	DE-A-25 16 973 (PH: * page 3, line 15 - * page 6, line 24 -	LIPS PATENTVERWALTUNG) - page 4, line 25 * - page 7, line 16 *	1 2	
•	EP-A-0 223 188 (FUG * abstract; figure	DITSU LIMITED) 4 *	1,2	
				TECHNICAL FIELDS
				SEARCHED (Int.Cl.5)
	The present search report has l	een drawn up for all claims		
	Place of search THE HAGUE	Date of completion of the search 5. August + 100/	922	examiner Pasua Garcia, L
X : part Y : part doc: A : tech O : non	CATEGORY OF CITED DOCUME icularly relevant if taken alone icularly relevant if combined with an iment of the same category inological background written disclosure mediate document	E : earlier patent do after the filing other D : document cited L : document cited	ple underlying the cument, but publiate in the application for other reasons	e invention ished on, or

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